


<b>Search Notes</b>  	<b>Application/Control No.</b>  10055457	<b>Applicant(s)/Patent Under Reexamination</b>  YUI, TOSHIYA
	<b>Examiner</b>  Mok, Alex W	<b>Art Unit</b>  2834

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
310	239	4/24/2007	AM

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST	4/24/2007	AM
PLUS	4/24/2007	AM

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>